

Quantum Coherence Lab Zumbühl Group



#### An elongated quantum dot as a distributed charge sensor

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- Recent preprint form Quantum Motion team
- Reflectometry measurements on Imec Si-MOS devices
- Elongated ("jellybean") quantum dot (EQD, approx. 340 nm long) is used for sensing dots on the left&right side of the dot (separated by 510 nm from each other)



# Device type (Imec)

- Si-MOS QD device (Imec) (no SEM/TEM images shown in the paper)
- n+ phosphorous doped polycrystalline silicon gates, 30 nm thick ('all-Silicon' approach, e-beam)
- Triple gate layer stack on 8 nm thermal SiO<sub>2</sub> film, patterned on high-R p-type Si wafer
- Gates isolated by 5nm ALD-based SiO<sub>2</sub>

Same type of gate stack as other Imec devices (different design):



(from N. I. Dumoulin Stuyck et al., 2021 Symposium on VLSI Circuits. 2021; p. 1-2)



#### Their device

- Confinement for 3 possible paths connecting Ohmics
- Barriers between elongated QD (EQD), QDs and reservoirs
- Plungers to control occupation of EQD, QDs and extension of 2DEG from under accumulation gates for reservoir (R), source (S) and drain (D)



- Oxford Instruments Triton fridge
- QDevil DACs&Thermalizing filters, sample holder
- Reflectometry with a VNA:

V<sub>RF</sub> drives single-e tunneling Currents between R&EQD if not in Coulomb blockade

→ complex Z of device changed →  $f_{res}$  & matching Z of resonator changed

DAC  $t_{sample} = 0.1 \text{ ms}$ ,  $f_{ramp} = 10 \text{ kHz}$ Start of DAC ramp triggers digitizer  $V_{IF}$  digitized @ 1 MS/s, preamp  $f_{LP} = 10 \text{ kHz}$ ,  $n_{avg} = 10$  $\rightarrow$  Tint =  $n_{avg}/f_{LP} = 1 \text{ ms}$ 



More detailed:

 $R_{\rm DC} = 49.99 \text{ k}\Omega, L = 820 \text{ nH}, \text{ and } C_{\rm c} = 22 \text{ pF}$ 

#### Single-electron box (SEB) operation

 Positive voltage at gate R → extend 2DEG close to active region of device from nearby ohmic contact



• Tune EQD plunger gate T above pinchoff, adjust tunnel rate via barrier gate B-RT:

To maximize signal, they later choose  $V_{B-RT} \simeq 0.3 V$ And  $V_T \simeq 0.7 V$  (not shown)



## Charge sensing of quantum dots

- EQD is operated as a SEB to sense first electron transition
- Signal-to-noise ratios  $SNR_{P2} = 10.7$   $SNR_{P3} = 14.6$  at one electron & 1 ms t.c. (at Sensor peak)





 Increase in V<sub>add</sub> on 4<sup>th</sup>->5<sup>th</sup> electron; lowest two ±z valley-orbit states



- Shift in VT vs. SEB transition linewidth
- V<sub>B-T3</sub> = 0.225 V (on)
- B-T3 off: electrons loaded via D

## Charge sensing coupled quantum dots (I)

Right reservoir 2DEG extended with gate D, scan P3 vs. B-34: •

0.65

- $\rightarrow$  honeycomb, center-center d<sub>right dot-EQD</sub> = 305 nm
- Next, DQD is formed with P3 and P4: ٠  $\rightarrow$  Latching along P3 axis, suggests P3-P4 or P4-D tunnel rates on order V<sub>P4</sub> (V) 0.70 0.75 0.80 0.85 0.90 of ramp frequency
- $\rightarrow d_{right dot-EQD} = 355 \text{ nm}$  seems to be Their limit here



## Charge sensing coupled quantum dots (II)

- Lastly, they form a triple dot with the EQD:
- Labels based on stability diagram simulation that uses ٠ Experimentally estimated lever arms & charging energies
- Lever arm ratios from fitted SEB peaks (red) • show close to zero P2-P3 crosstalk V<sub>IF</sub> (mV)
- One SEB charge transition is capacitively • shifted by both P2 and P3  $\rightarrow$  EQD extends approximately over region T



## Simulated quantum-mechanical electron densities

- Self-consistent Schroedinger-Poisson solver to evaluate quantum-mechanical electron densities (QMED)
- $\rightarrow$  Estimate shapes of many-electron charge states
- EQD length obtained from simulated  $1\sigma$  and  $2\sigma$  contours  $\rightarrow$  Studied for different #electrons (different V<sub>T</sub>)



$$x_{\rm EQD} = an_{\rm T}^{-1/2} + b$$

a<0 n<sub>T</sub>: sim. Electron number b = 347 nm b = 339 nm



→When only gate T is biased, the EQD length increases monotonically
 →With other gates involved, EQD length behaves more complicated (e.g. B-RT gate pulls electrons)

#### Summary&Outlook

- Demonstrated EQD as a rf-SEB charge sensor sensing QDs up to 355 nm away from EQD (QD-QD distance >700 nm), supported by simulations
- Potential for scalable QD unit cells, e.g. with a single sensor for multiple closeby quantum dots → novel QD unit cell layout requiring potentially less gate structures for readout
- Another potential application: Mid-ranged spin qubit coupler [1]

[1] F. Malinowski et al., Nat. Comms. 2019

